

Session QQ

Optical Characterization and Device Modeling

Chairman:

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Optical characterization of microwave devices has the potential for very large bandwidth compared to electronic techniques and is noninvasive. Direct illumination of microwave devices has important implications in the interfacing of optical and microwave components and modeling of these devices has stimulated much interest. This session will present new results on the illumination of devices for characterization and modeling.



**1:30 p.m.–3:00 p.m., Thursday, June 17, 1993
Room 202**

